



Vishay Siliconix

# N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)	
	0.0235 at V <sub>GS</sub> = 10 V	27.5		
100	0.0245 at V <sub>GS</sub> = 7.5 V	27	7.7 nC	
	0.0315 at V <sub>GS</sub> = 4.5 V	24		

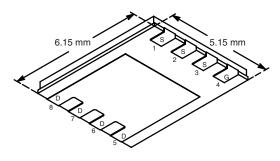
### **FEATURES**

- Halogen-free According to IEC 61249-2-21
- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> Tested 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



FREE

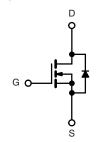
### PowerPAK® SO-8



Ordering Information: Si7456CDP-T1-GE3 (Lead (Pb)-free and Halogen-free)

### **APPLICATIONS**

- DC/DC Primary Side Switch
- Telecom/Server 48 V, Full/Half-Bridge dc-to-dc



N-Channel MOSEFT

<b>ABSOLUTE MAXIMUM RATINGS</b>	$T_A = 25  ^{\circ}C$ , unles	ss otherwise no	ted		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	100	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20		
	T <sub>C</sub> = 25 °C		27.5		
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	I .	22		
Continuous Diam Current (1) = 130 C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	10.3 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		8.2 <sup>b, c</sup>	Α	
Pulsed Drain Current		I <sub>DM</sub>	50	^	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	25		
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	'S	4.5 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	15		
Single Pulse Avalanche Energy	L = 0.1 IIII1	E <sub>AS</sub>	11.2	mJ	
	T <sub>C</sub> = 25 °C		35.7		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	22.8	W	
Maximum rower Dissipation	T <sub>A</sub> = 25 °C	, p	5.0 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) <sup>d, e</sup>			260	]	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	$R_{thJA}$	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	2.9	3.5	]	

#### Notes:

- a. Based on  $T_C$  = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- d. See solder profile (<u>www.vishay.com/ppg?73257</u>). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.

## Si7456CDP

# Vishay Siliconix



<b>SPECIFICATIONS</b> $T_J = 25  ^{\circ}\text{C}$ ,			N#:	T	Mess	11	
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static  Drain-Source Breakdown Voltage	V	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	100	1	1	V	
V <sub>DS</sub> Temperature Coefficient	$V_{DS}$ $\Delta V_{DS}/T_{J}$	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	100	47		V	
50 .		$I_D = 250 \mu A$				mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	V V I 050 ·· A	4.0	- 5.4			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.2		2.8	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1	μΑ	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	<b>,</b>	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
		$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		0.0195	0.0235		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 9 \text{ A}$		0.0204	0.0245		
		$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		0.026	0.0315	Ī	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		25		S	
Dynamic <sup>b</sup>			•		•		
Input Capacitance	C <sub>iss</sub>			730			
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		425		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			30			
·		$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		15	23		
Total Gate Charge	Qg			11.6	18		
3.		20 7 00 - 7 0 - 7 1		7.7	12	nC	
Gate-Source Charge	Q <sub>qs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		2.0			
Gate-Drain Charge	Q <sub>gd</sub>			3.7			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	1	5	10	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			9	18		
Rise Time	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_1 = 5 \Omega$		13	26	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_a = 1 \Omega$		22	44		
Fall Time	t <sub>f</sub>	•		10	20		
Turn-On Delay Time	t <sub>d(on)</sub>			11	22		
Rise Time	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_1 = 5 \Omega$		14	28		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 7.5 \text{ V}, R_g = 1 \Omega$		20	40		
Fall Time	t <sub>f</sub>	Z SEII 9		9	18		
Drain-Source Body Diode Characteristic					1 .0		
Continuous Source-Drain Diode Current I <sub>S</sub> T <sub>C</sub> = 25 °C				25			
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	0			50	Α	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 4 A		0.79	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	19-411	1	34	68	ns	
	Q <sub>rr</sub>			-	-		
Body Diode Reverse Recovery Charge	+	$I_F = 5$ A, $dI/dt = 100$ A/ $\mu$ s, $T_J = 25$ °C	<u> </u>	32	64	nC	
Reverse Recovery Fall Time	1	t <sub>a</sub> t <sub>b</sub>		16		ns	
Reverse Recovery Rise Time	ι <sub>b</sub>			18			

#### Notes:

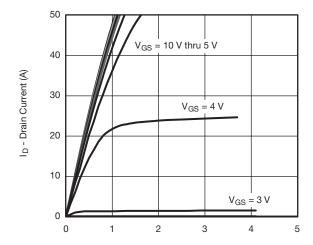
- a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

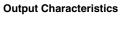


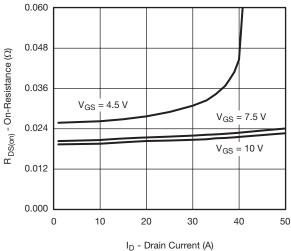
# Vishay Siliconix

### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

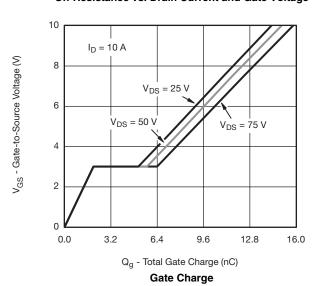


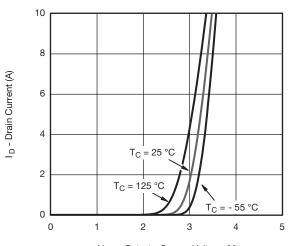
V<sub>DS</sub> - Drain-to-Source Voltage (V)





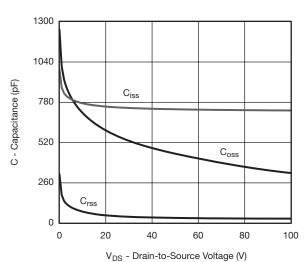
On-Resistance vs. Drain Current and Gate Voltage



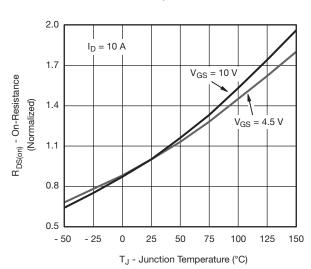


V<sub>GS</sub> - Gate-to-Source Voltage (V)

### **Transfer Characteristics**



Capacitance



On-Resistance vs. Junction Temperature

0.10

0.00

# Si7456CDP

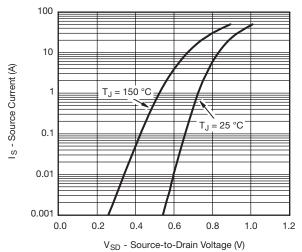
# Vishay Siliconix

# Visitay Silicoriix

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



9



## 

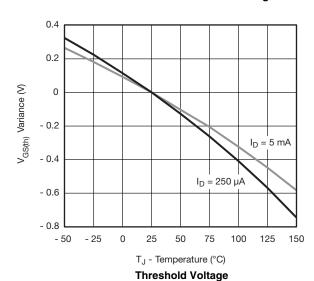
3

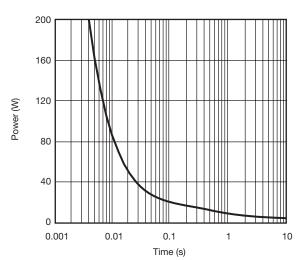
V<sub>GS</sub> - Gate-to-Source Voltage (V)

5

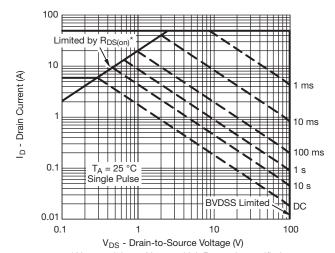
On-Resistance vs. Gate-to-Source Voltage

### Source-Drain Diode Forward Voltage





Single Pulse Power, Junction-to-Ambient



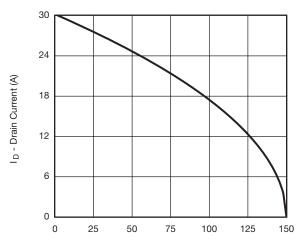
\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient



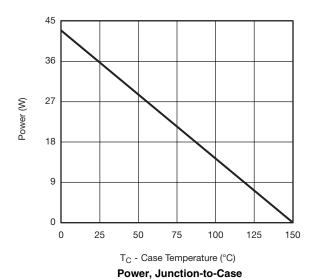
Vishay Siliconix

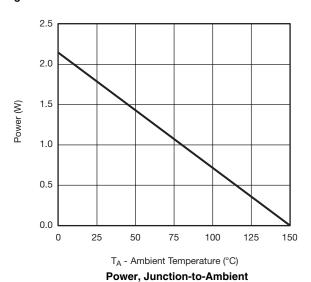
### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



T<sub>C</sub> - Case Temperature (°C)

### **Current Derating\***





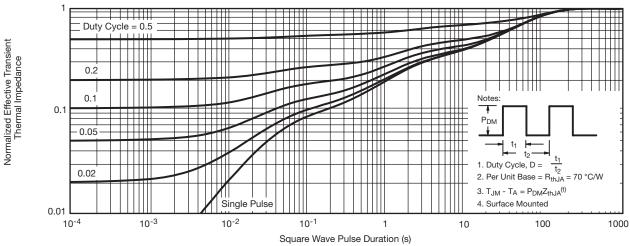
<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

## Si7456CDP

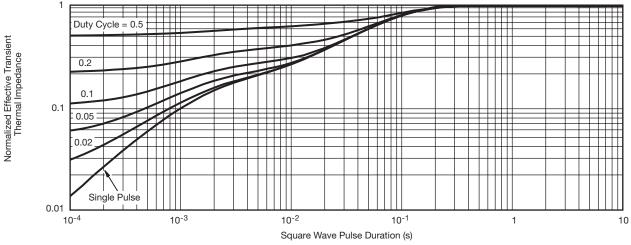
## Vishay Siliconix



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <a href="https://www.vishay.com/ppg265941">www.vishay.com/ppg265941</a>.



Vishay

### **Disclaimer**

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Revision: 18-Jul-08

Document Number: 91000 www.vishay.com